

Fast switching diode chip in EMCON 3 -Technology

Features:

- 650V EMCON 3 technology 65 μm chip
- Soft, fast switching
- Low reverse recovery charge
- Small temperature coefficient
- Qualified according to JEDEC for target applications

Recommended for:

- Power module
- Discrete components



Applications:

- Drives
- White goods
- Resonant applications

Chip Type	V _R	/ _{Fn} ¹⁾	Die Size	Package
SIDC03D65C8	650V	10A	1.82 x 1.82 mm ²	sawn on foil

", nominal forward current at Tc = 100°C, not subject to production test - verified by design/characterisation

Mechanical Parameters

Die size		1.82 x 1.82			
Area total		3.31	mm ²		
Anode pad size		1.39 x 1.39			
Thickness		65	μm		
Wafer size		200	mm		
Max. possible chips pe	er wafer	8499	8499		
Passivation frontside		Photoimide			
Pad metal		3200 nm AlSiCu			
Backside metal		Ni Ag –system			
Die bond		Electrically conductive epoxy glue and soft solder			
Wire bond		Al, ≤500µm			
Reject ink dot size		Ø 0.65mm; max 1.2mm			
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 25° < 6 month			
	for open MBB bags	Acc. to IEC62258-3: Atmosphere >99% Nitrogen or ine Humidity <25%RH, Temperature 17°C – 25°C, < 6 m			



Maximum Ratings

Parameter	Symbol	Condition	Value	Unit	
Repetitive peak reverse voltage	V _{RRM}	<i>T</i> _{vj} = 25 °C	650	V	
Continuous forward current	I _F	<i>T</i> _{vj} < 150°C	1)	_	
Maximum repetitive forward current ²⁾	I _{FRM}	<i>T</i> _{vj} < 150°C	20	A	
Operating junction temperature	T _{vj}		-40+175	°C	

¹⁾ depending on thermal properties of assembly

²) not subject to production test - verified by design/characterisation

Static Characteristics (tested on wafer), T_{vj} = 25 °C

Parameter	Symbol	Conditions	Value			Unit
Farameter			min.	typ.	max.	Unit
Reverse leakage current	I _R	V _R =650V			0.14	μA
Cathode-Anode breakdown Voltage	V _{BR}	I _R =0.25mA	650			V
Forward voltage drop	VF	I _F =10A	1.23	1.55	1.87	

Electrical Characteristics (not subject to production test - verified by design/characterization)

Parameter	Symbol	Conditions	Value			Unit
Falameter			min.	typ.	max.	Unit
Forward voltage drop	V _F	$I_{\rm F}$ =10A, $T_{\rm vj}$ =150°C		1.5		V

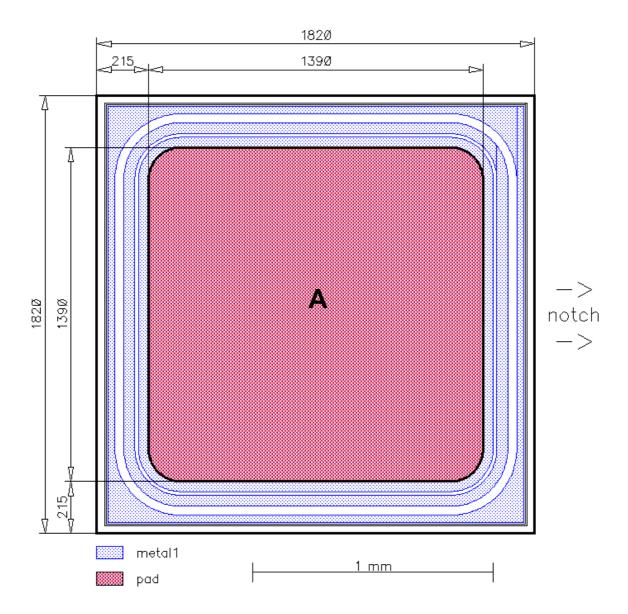
Further Electrical Characteristics

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

This chip data sheet refers to the device data sheet	tbd	tbd



Chip Drawing



Die-Size 1820 um x 1820 um

A: Anode pad



Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Version	Subjects (major changes since last revision)	Date

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